

PATENT APPLICATION

Express Mail Label No.: EV 725 078 **2005 Rec'd PCT/PTO 07 OCT 2005**
10/552517
IN THE U.S. PATENT AND TRADEMARK OFFICE

October 7, 2005

Applicant: Hiroshi SEKIYA

For : STAINING PREVENTION METHOD FOR DRY PART OF PAPER
MACHINE AND STAINING INHIBITOR USED FOR THE METHOD

PCT International Application No.: PCT/JP2004/004462

PCT International Filing Date: March 29, 2004

U.S. Application No.

(if known, see 37 CFR 1.5): Unknown

Atty. Docket No.: 4414.P0684US

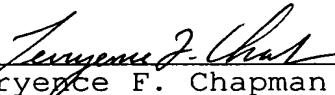
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INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

Respectfully submitted,



Terryence F. Chapman

TFC/smd

FLYNN, THIEL, BOUTELL & TANIS, P.C. 2026 Rambling Road Kalamazoo, MI 49008-1631 Phone: (269) 381-1156 Fax: (269) 381-5465	Dale H. Thiel David G. Boutell Ronald J. Tanis Terryence F. Chapman Mark L. Maki Liane L. Churney Brian R. Tumm Steven R. Thiel Donald J. Wallace Kevin L. Pontius Sidney B. Williams, Jr.	Reg. No. 24 323 Reg. No. 25 072 Reg. No. 22 724 Reg. No. 32 549 Reg. No. 36 589 Reg. No. 40 694 Reg. No. 36 328 Reg. No. 53 685 Reg. No. 43 977 Reg. No. 37 512 Reg. No. 24 949
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Encl: Copy of International Search Report
Form PTO-1449 and one copy of each reference listed
thereon

336.05/03

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INFORMATION DISCLOSURE CITATION	Applicant: Hiroshi SEKIYA Ser.No.: Unknown Conf. No.: Unknown Group: Unknown	Filed: Unknown Atty. Docket No.: 4414.P0684US Date: October 7, 2005
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U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA	6 468 394	10-22-2002	SEKIYA et al
	AB			
	AC			
	AD			
	AE			
	AF			
	AG			
	AH			
	AI			
	AJ			
	AK			

FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL	EP 1 124 006 A1	08-16-2001	SEKIYA	
	AM	JP 62-215098	09-21-1987		NO
	AN	JP 7-279081	10-24-1995		NO
	AO	JP 2000-96478	04-04-2000		NO
	AP	JP 2000-345489	12-12-2000		NO

NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
	AR	

EXAMINER SIGNATURE	DATE CONSIDERED
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.